

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10769930	CHUNG ET AL.
	Examiner	Art Unit
	ALI BAYAT	2624

SEARCHED

Class	Subclass	Date	Examiner
382	100,115,119,121-122,187,219,305	2/26/08	A.B
348	161	2/26/08	A.B
345	179	2/26/08	A.B
73	865.4	2/26/08	S.B
178	18.01	2/26/08	A.B
updated above		6/19/08	A.B

SEARCH NOTES

Search Notes	Date	Examiner
EAST(US-PGPUB; USPAT; EPO; JPO; DERWENT; USOCR; FPRS), Inventor name searched,see text search history print out.	2/26/08	A.B
updated above plus IEEE EXPLORE DATABASE searched.	6/19/08	A.B

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
US-PGPUB	see Interference search history print out.	2/26/08	A.B
	updated above	6/19/08	A.B